

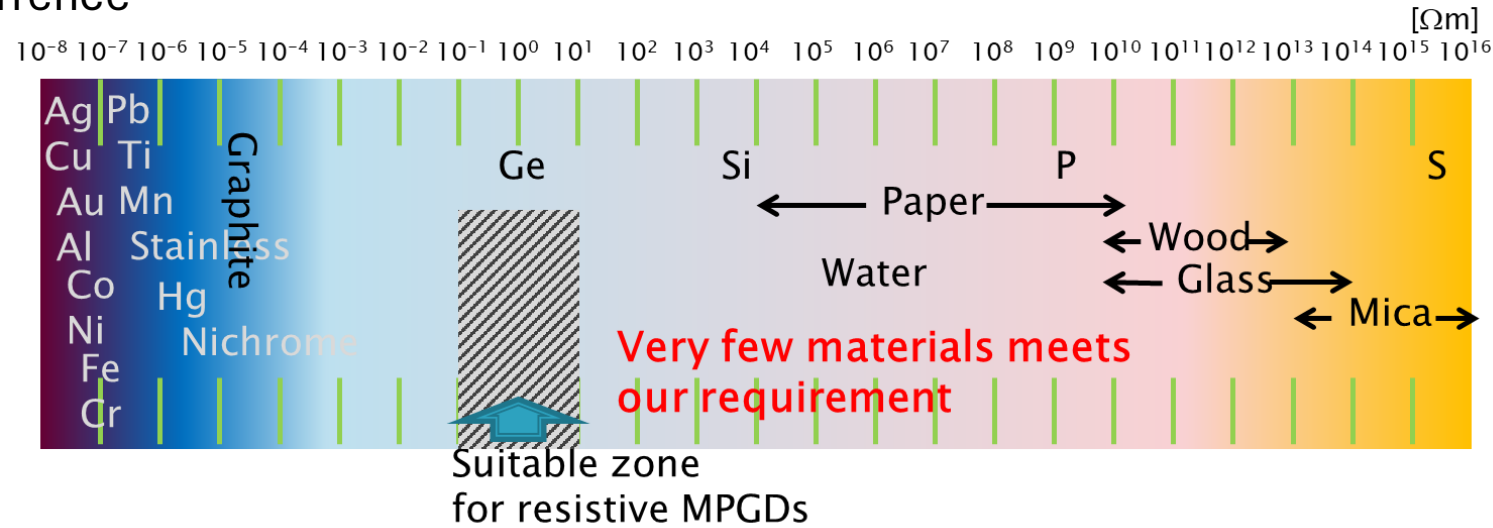
Resistive Electrodes

G. Morello on behalf of WG3

DRD1 Meeting, January 31st 2024

Resistivity

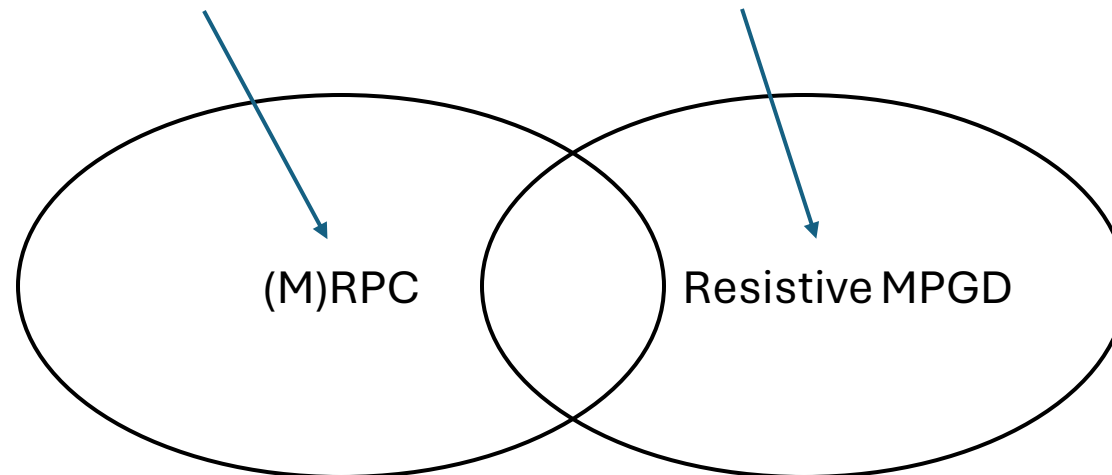
The resistive electrodes were introduced in particle detectors with the aim to localize the reduction of the electric field due to a discharge occurrence



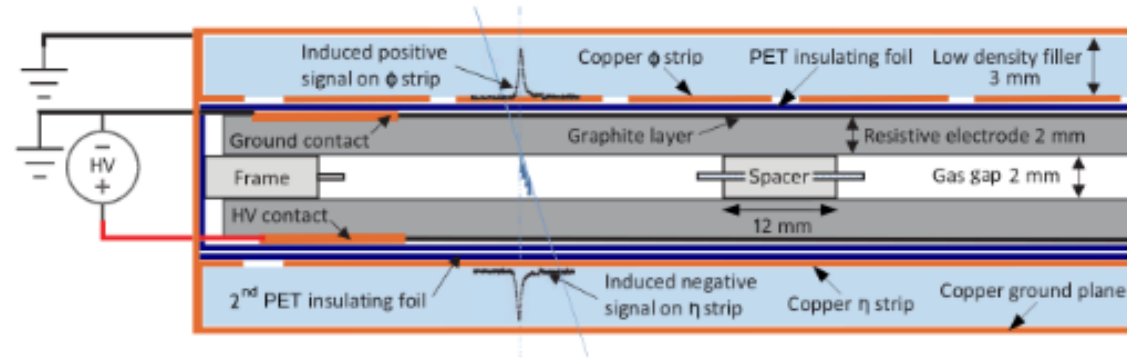
<https://agenda.infn.it/event/18156/timetable/?view=standard>

Several technologies for particle detectors are nowadays based on resistive electrodes.

It is worth distinguish between **bulk resistivity (Ωm)** and **surface resistivity (Ω/\square)** when $H \ll W, L$



Resistive Plate Counter



arXiv:2103.01029v1

FEW EXAMPLES of resistive materials used in RPCs

| Experiment | Resistive electrode | Gas mixture |
|------------|--|--|
| L3 | Oiled Bakelite $2E11 \Omega\text{cm}$ | Ar/ iC_4H_{10} / $C_2H_2F_4$ 59/35/6 |
| Belle | Float glass $1E12 \div 1E13 \Omega\text{cm}$ | Ar/ iC_4H_{10} / $C_2H_2F_4$ 30/8/62 |
| Alice TOF | Soda-lime glass $1E13 \Omega\text{cm}$ | $C_2H_2F_4/SF_6$ 93/7 |

Source: M. Abbrescia, V. Peskov, P. Fonte, Resistive Gaseous Detectors, Wiley-VCH, 2018

Other alternative materials under study are lower resistive glasses, ceramics, plastic with resistivity around $1E10 \Omega\text{cm}$ (see Wang Yi and Giulio Aielli talks)

Semi-conductors (ex. GaAs) are good candidates as the resistivity is lower ($1.4E8 \Omega\text{cm}$) → G. Aielli's talk

Resistive Plate Counter

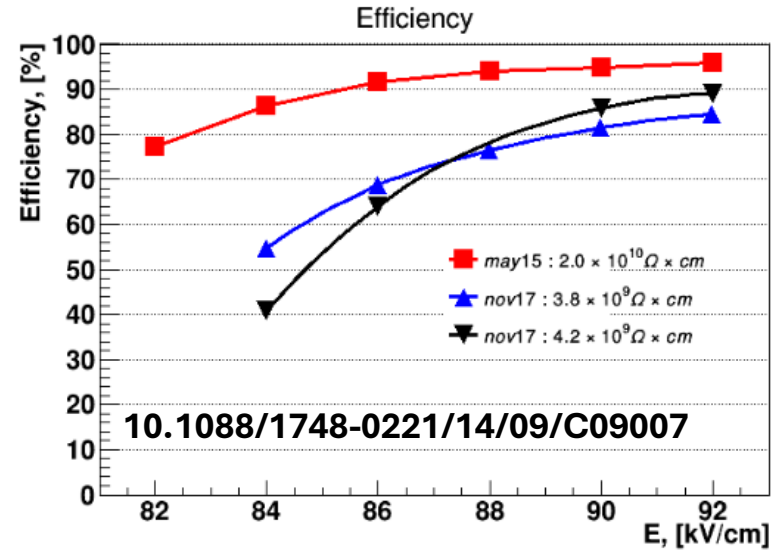


Figure 3. RPC efficiency as function of the field strength for three RPC detectors performed with two readout systems: squares — MAXIM3760+CAEN TDC, triangles — PADI-10. The corresponding bulk resistivities of the ceramic plates on floating potential are given in the legend.

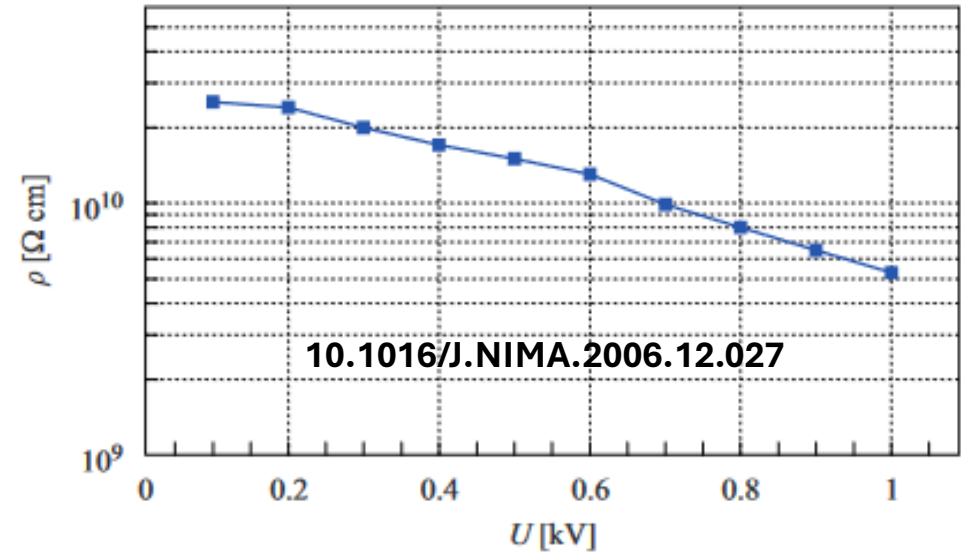
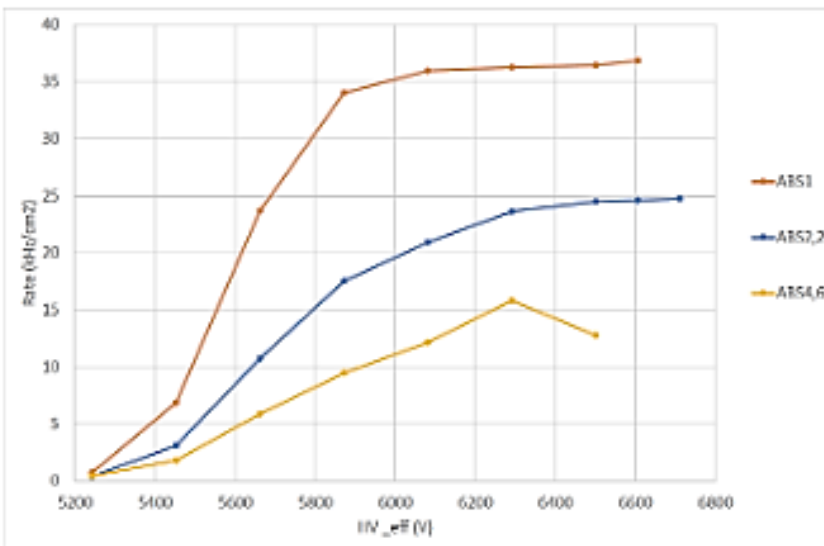


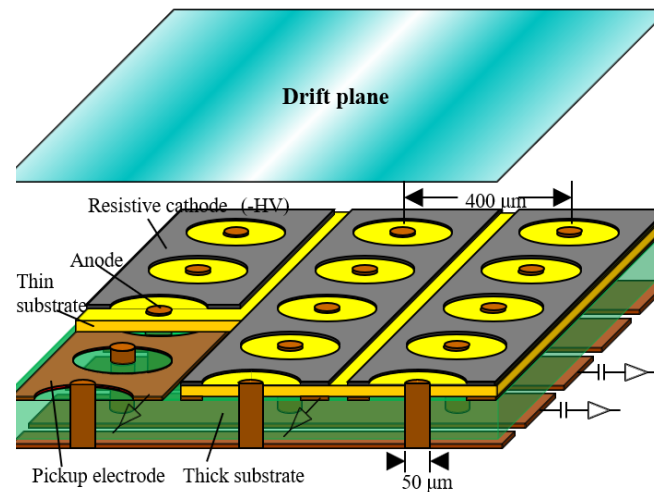
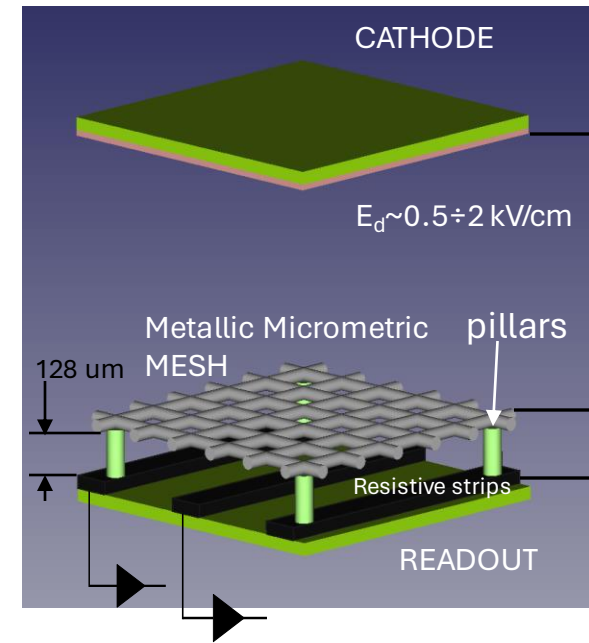
Fig. 3. Dependence of the bulk resistivity of phosphate glass on high voltage.



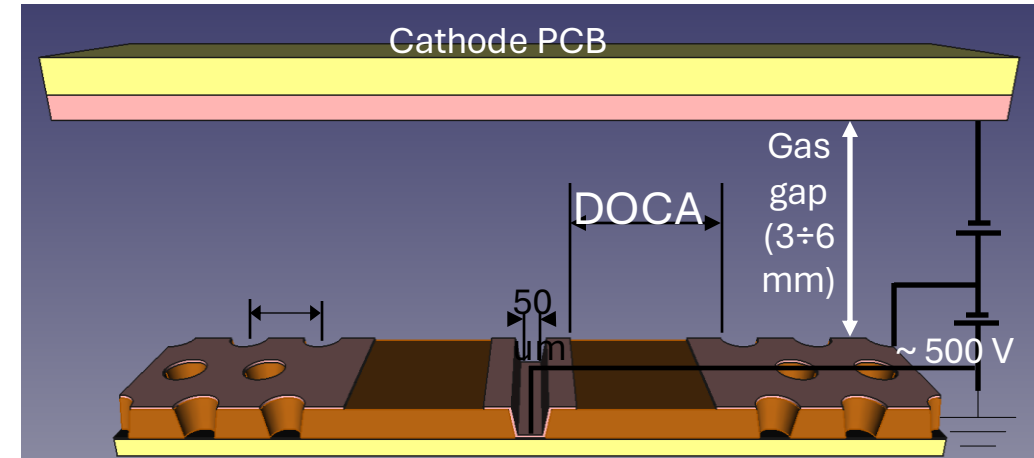
10.1088/1748-0221/15/12/C12004
 Figure 7. Measured counting rate for three different value of the absorption factor as a function of the high voltage.

Further interesting
 developments in
[HTTP://CDS.CERN.CH/
 RECORD/2319919](http://cds.cern.ch/record/2319919)

Resistive MPGDs



https://indico.cern.ch/event/756297/contributions/3149140/attachments/1723844/2783880/u-PIC_ochi_180927.pdf



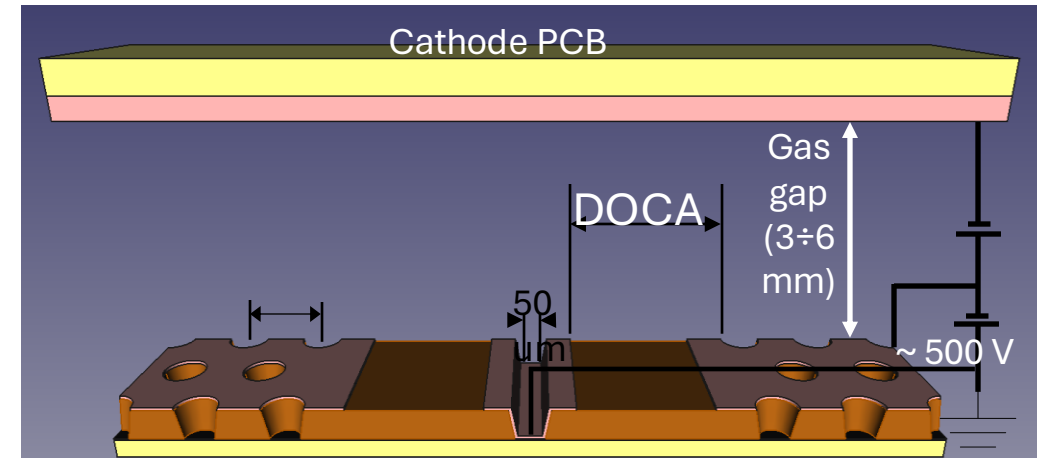
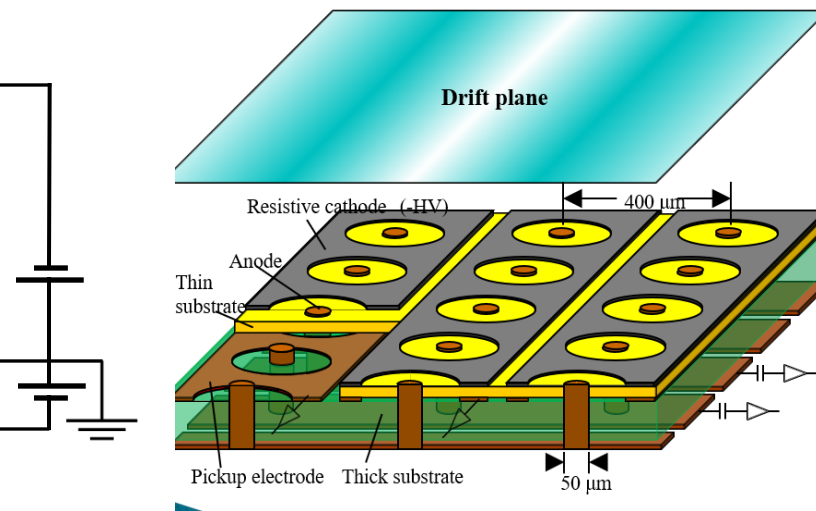
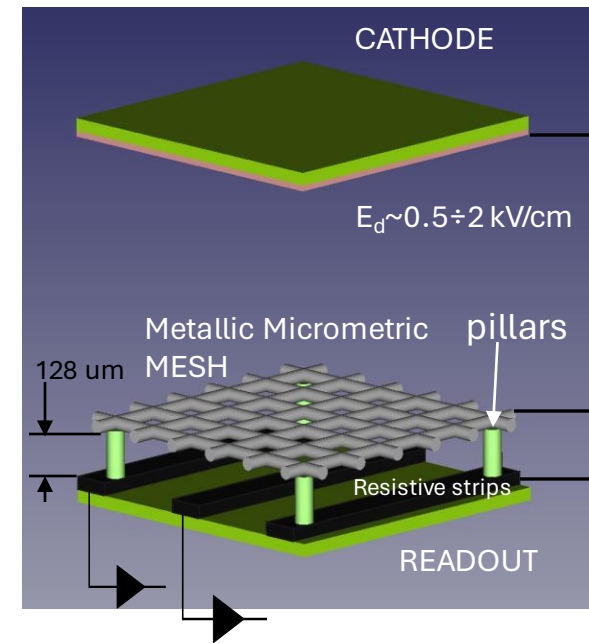
ATLAS MicroMegas were the first MPGD introducing a resistive stage by screen printing ($O(1 \text{ M}\Omega/\square)$), example recently followed for RETGEM detectors.

Other MPGDs start exploiting the properties of Diamond-Like Carbon (DLC), an amorphous layer of graphite, already extensively used in industry for its mechanical properties. In our case we care the electrical properties.

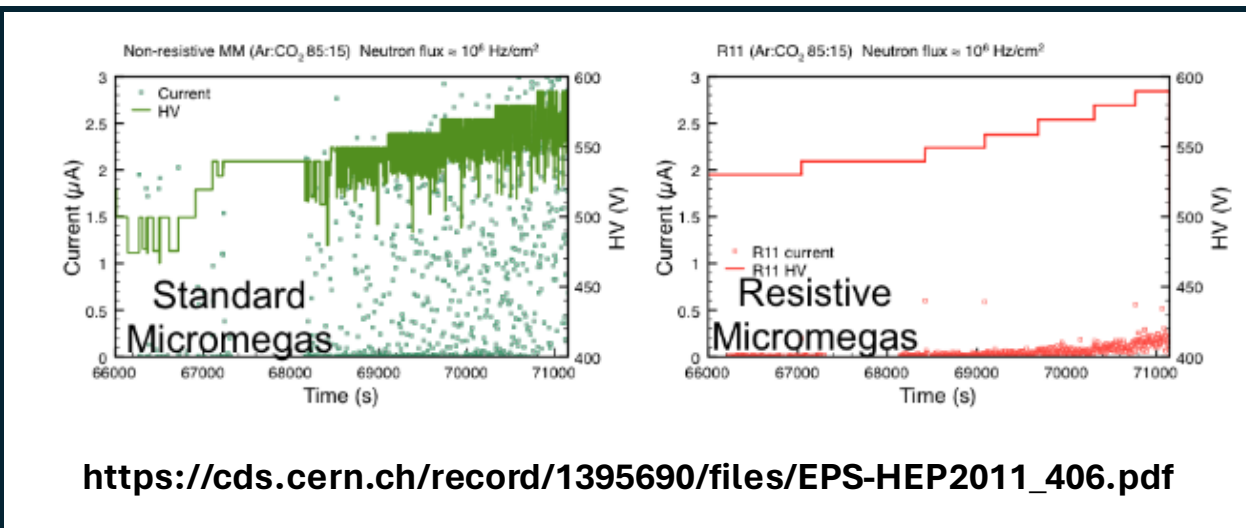
Needing different values of surface resistivity: around $10 \text{ M}\Omega/\square$ for the MM and around $100 \text{ M}\Omega/\square$ for the u-RWELL

The segmentation of the resistive layer and/or a more dense grounding network brings to larger rate capability

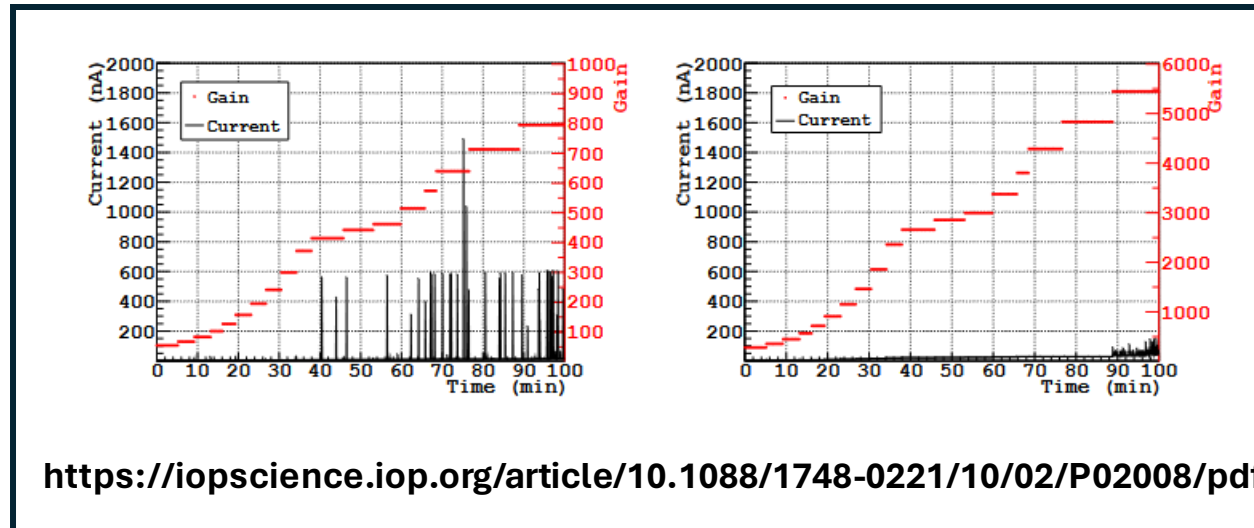
Micro-Pattern Gaseous Detectors



https://indico.cern.ch/event/756297/contributions/3149140/attachments/1723844/2783880/u-PIC_ochi_180927.pdf



https://cds.cern.ch/record/1395690/files/EPS-HEP2011_406.pdf



<https://iopscience.iop.org/article/10.1088/1748-0221/10/02/P02008/pdf>

Surface Resistive Plate Counter

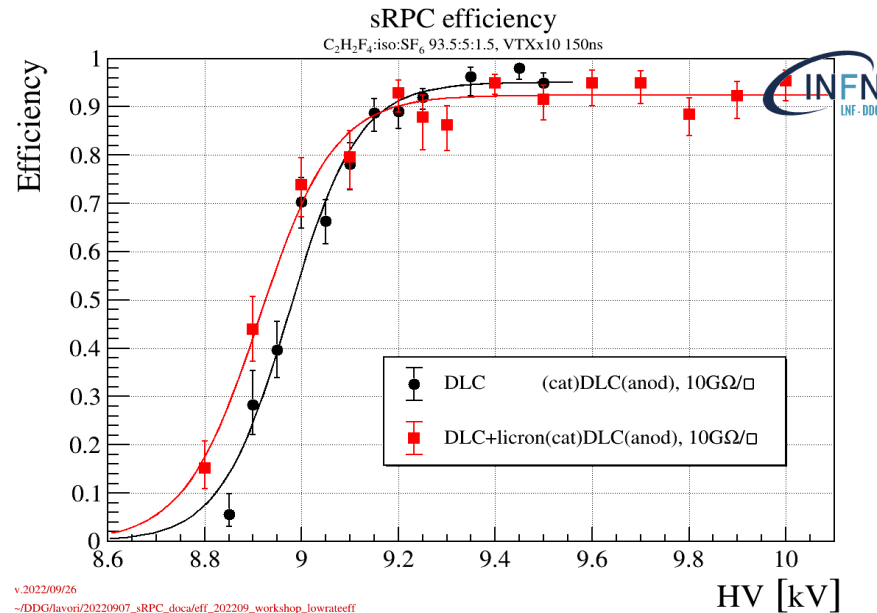


Glass $140 \times 78 \text{ mm}^2$
DLC $120 \times 64 \text{ mm}^2$

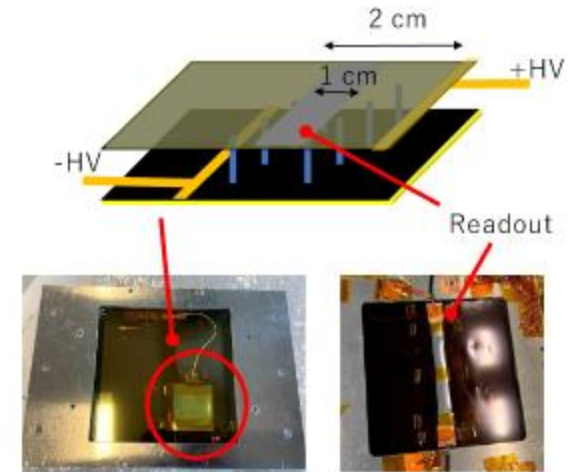
DLC-based RPC:

- **From bulk resistivity to surface resistivity:** easy tunable resistivity w.r.t. bakelite or glass
- μ -RWELL inspired **High Rate schemes**
- Flexible substrate

A promising novel technology, from MPGD material and technology experience.



v_2022/09/26
~/DDG/favori/20220907_sRPC_docs/eff_202209_workshop_lowrateeff



<https://arxiv.org/pdf/2401.13553.pdf>

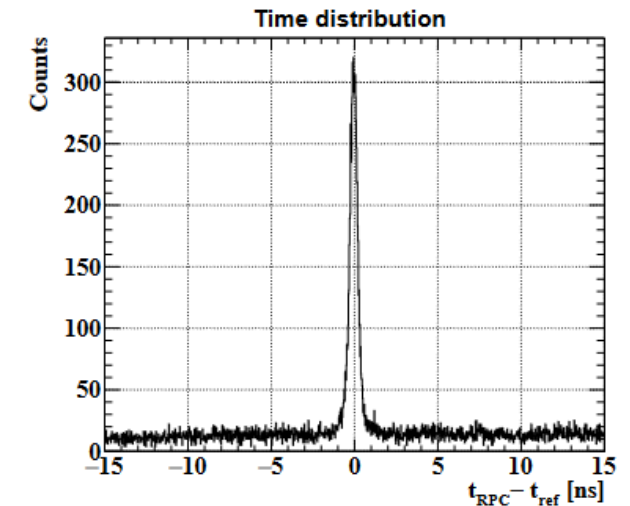


Figure 13: Time difference between the RPC and the trigger counter in the high-rate measurement. The peak comes from detected positrons and the baseline comes from accidental muon hits.

My personal view...

Classical detectors, bulk resistivity

MPGD, surface resistivity

RPC, MRPC

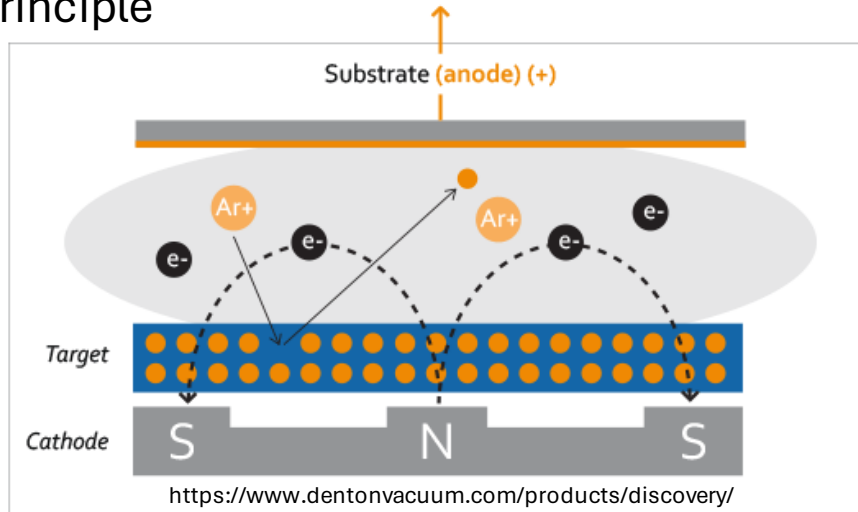
sRPC, RPWELL

Resistive MicroMegas, u-PIC,
u-RWELL, RETGEM

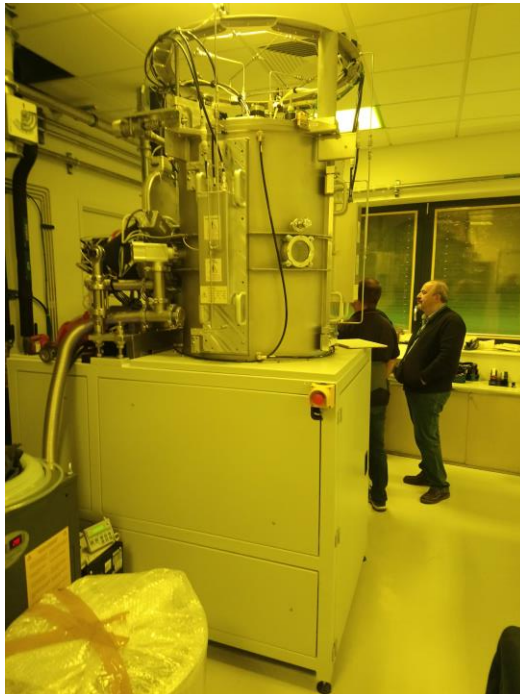
DRD1 PRODROME!

The magnetron sputtering machine

Working principle



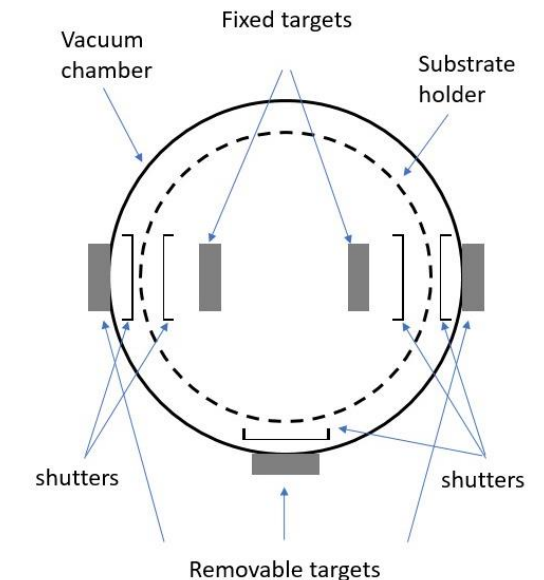
- The field creates ion-electron pairs in the plasma
- The electrons are accelerated and further ionize the plasma generating new ions
- A magnetic field concentrates the ions in a peculiar region of the target (speed track)
- The ions drift towards the target and by collision the material is extracted flying all over the vacuum chamber



The graphite target



The three external cathodes



Machine co-funded by CERN and INFN. R&D led by INFN LNF, Roma3 and Na

DLC tests: modus operandi

SAMPLES

- APICAL foil dried in the oven (at least 16h at 100°C)
- Three rectangular samples, 15 x 10 cm² (machine operating in oscillation mode), to check the uniformity of the deposition along z
- A small 1.5 x 1.5 cm² glass next to each sample for thickness measurement

RUN

- Pure Ar-based plasma surface treatment (plasma etching)
- Pure Ar-based pre-sputtering process
- Sputtering process

POST RUN

- Resistivity measurements
- Baking of one sample from each run (2h at 220°C) to simulate the thermal shock during detector manufacturing
- Monitoring of the resistivity during the following days (stability check)



Repetitivity and stability with N2

First tests with N2 answered to two urgent questions:

- 1) Standing the same deposition parameters, will the resistivity be the same or will it change?
- 2) How does the resistivity change along the time?

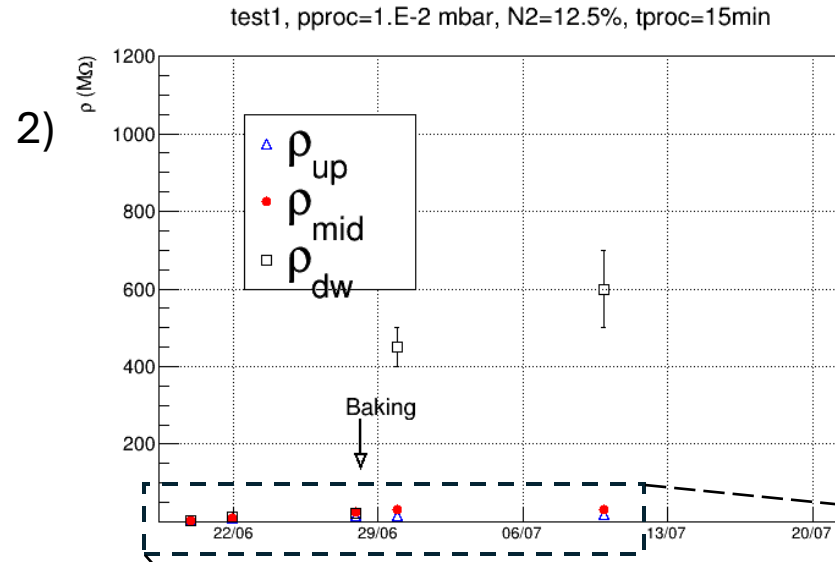
| Test | | | 20/06 | 22/06 |
|------|---|--|-----------------|-------------|
| 1) | | | | |
| 1 | $P_{\text{proc}} = 1.E-2$ $N_2 = 12.5\%$ $T_{\text{proc}} = 15\text{min}$ | ρ_{bot} ρ_{mid} ρ_{up} | 2.7 2.5 2 | |
| 2 | $P_{\text{proc}} = 1.E-2$ $N_2 = 12.5\%$ $T_{\text{proc}} = 15\text{min}$ | ρ_{bot} ρ_{mid} ρ_{up} | 2.5 3 2 | |
| 3 | $P_{\text{proc}} = 1.E-2$ $N_2 = 12.5\%$ $T_{\text{proc}} = 15\text{min}$ | ρ_{bot} ρ_{mid} ρ_{up} | | 3 3 4 |

Measurements in Mohm/sq.

Quite satisfactory repetition capability

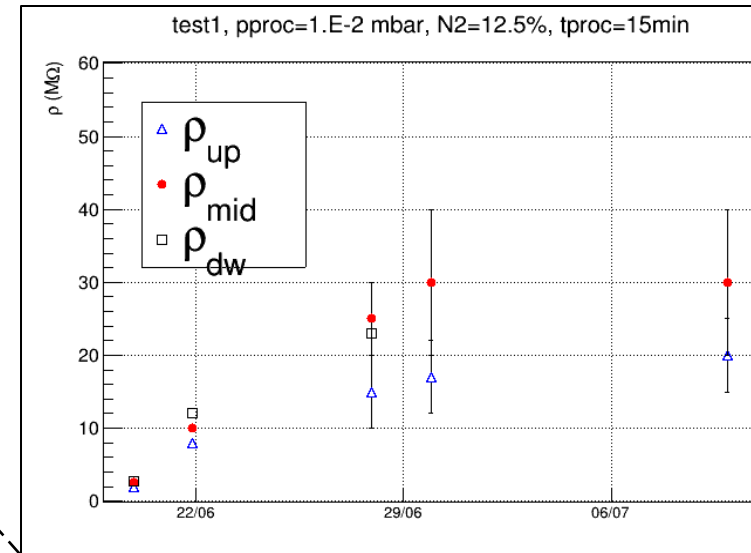
Further confirmations for other dep.

conditions



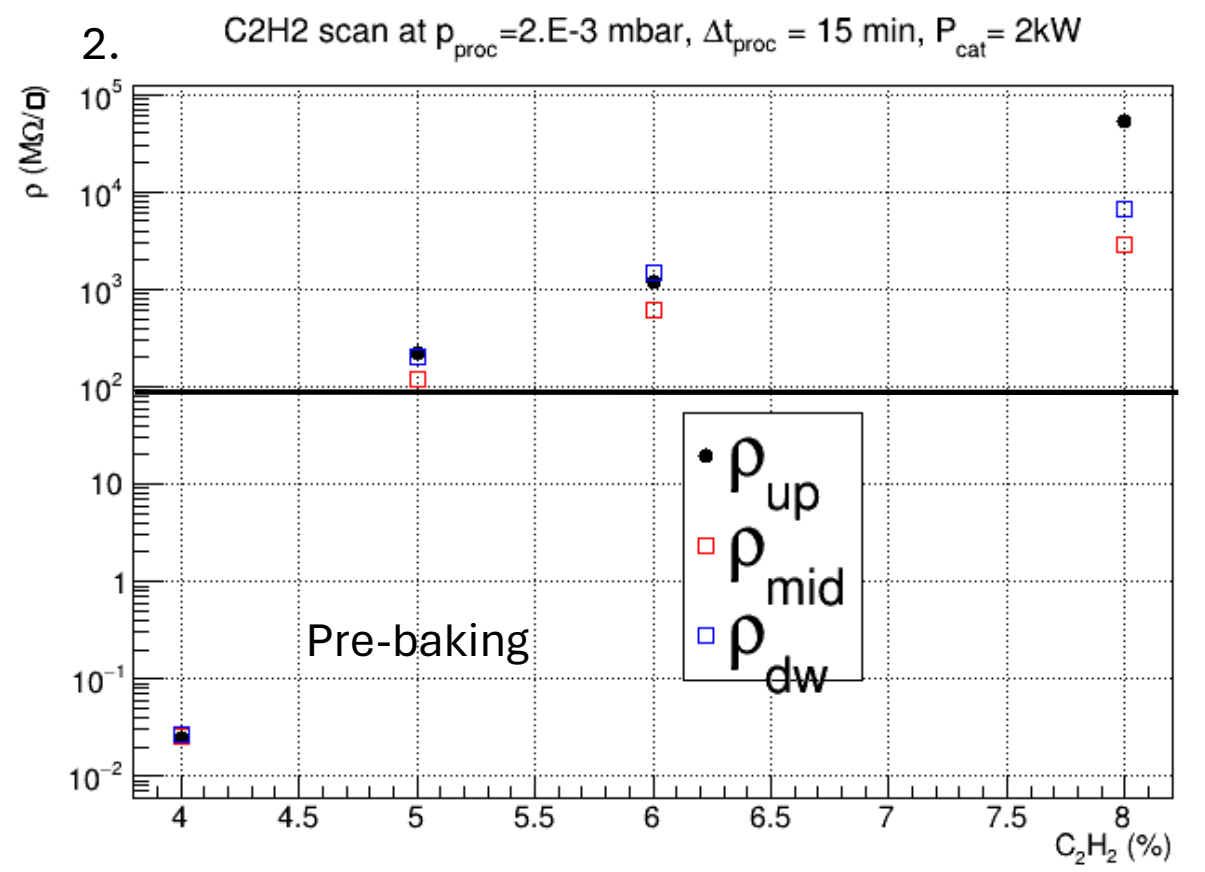
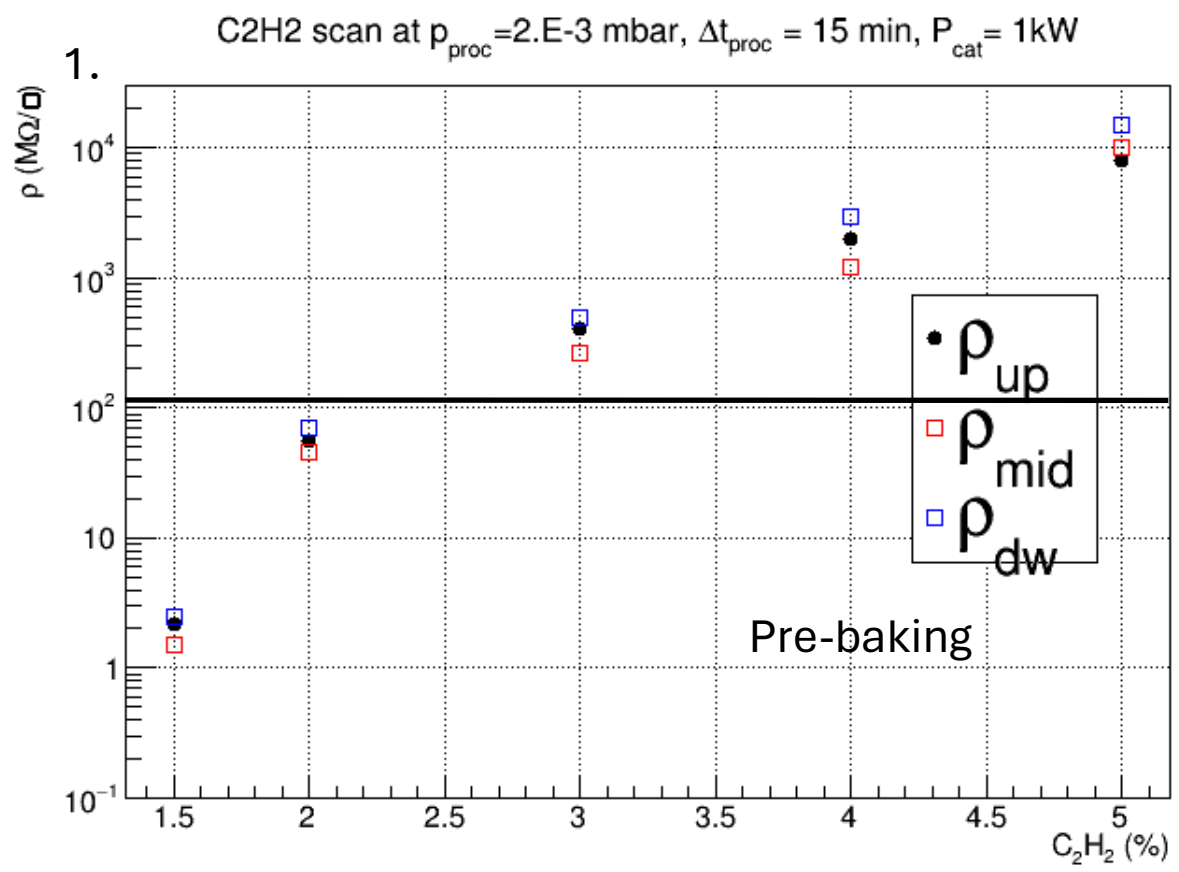
We baked one of the three sample and the resistivity jumped up of a factor 200

Anyway a drift towards upper values of resistivities is observed after few days
WE NEED STABLE VALUES



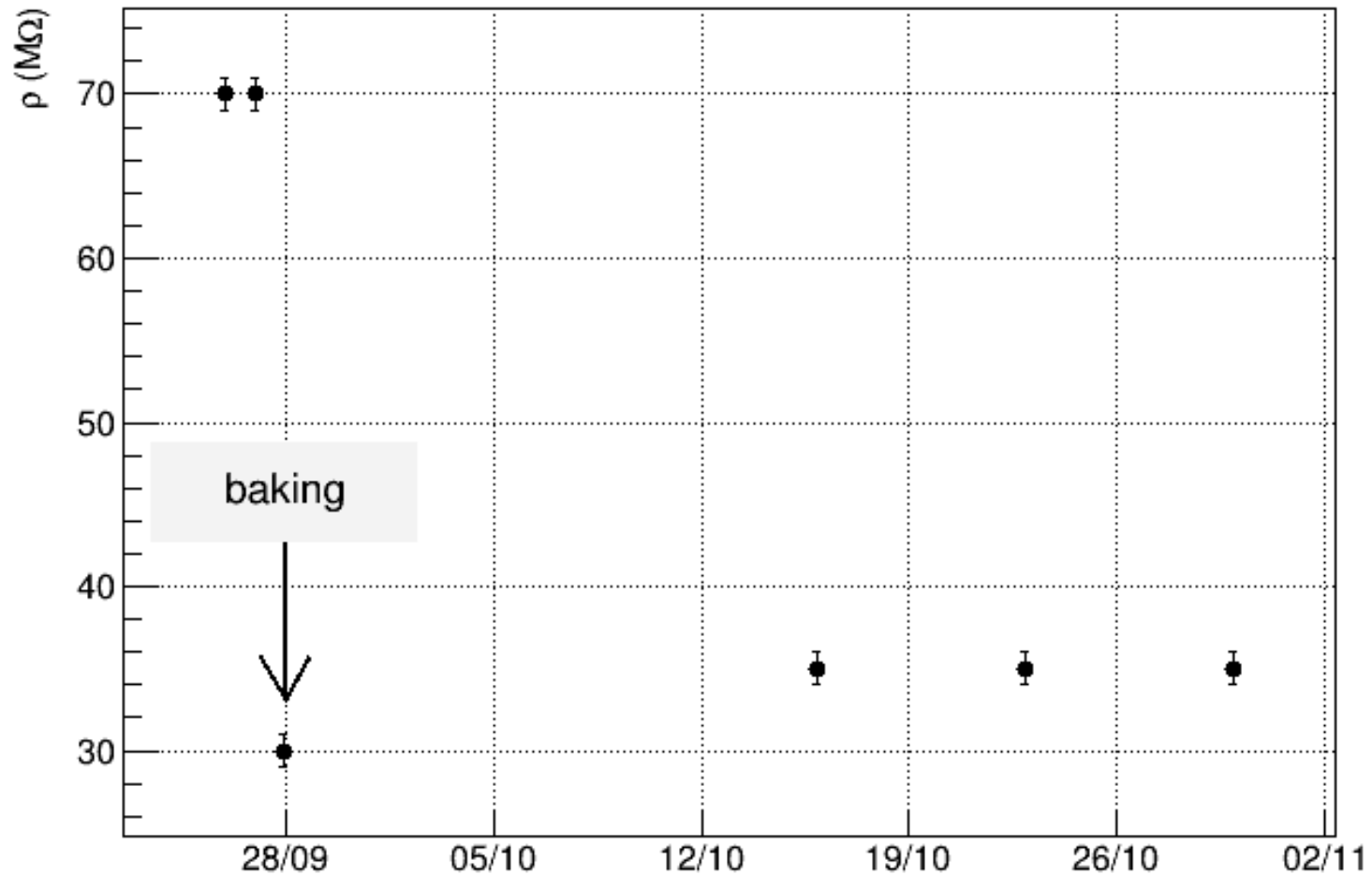
Summary of the test with C₂H₂ (Sept. 2023)

1. Scans in acetylene percentage (1.5% - 5%) at $p_{\text{proc}} = 2.E-3$ mbar, $t_{\text{dep}} = 15$ m and $P_{\text{cat}} = 1$ kW
2. Scans in acetylene percentage (4% - 8%) at $p_{\text{proc}} = 2.E-3$ mbar, $t_{\text{dep}} = 15$ m and $P_{\text{cat}} = 2$ kW
3. Test at different deposition time (15 m – 240 m) with 4% of C₂H₂ at $p_{\text{proc}} 8.E-3$ and $P_{\text{cat}} = 1$ kW
4. Repetitivity tests (C₂H₂ 3%, $p_{\text{proc}} = 2.E-3$, $P_{\text{cat}} = 1$ kW, $t_{\text{dep}} = 22.5$ m)
5. Uniformity tests



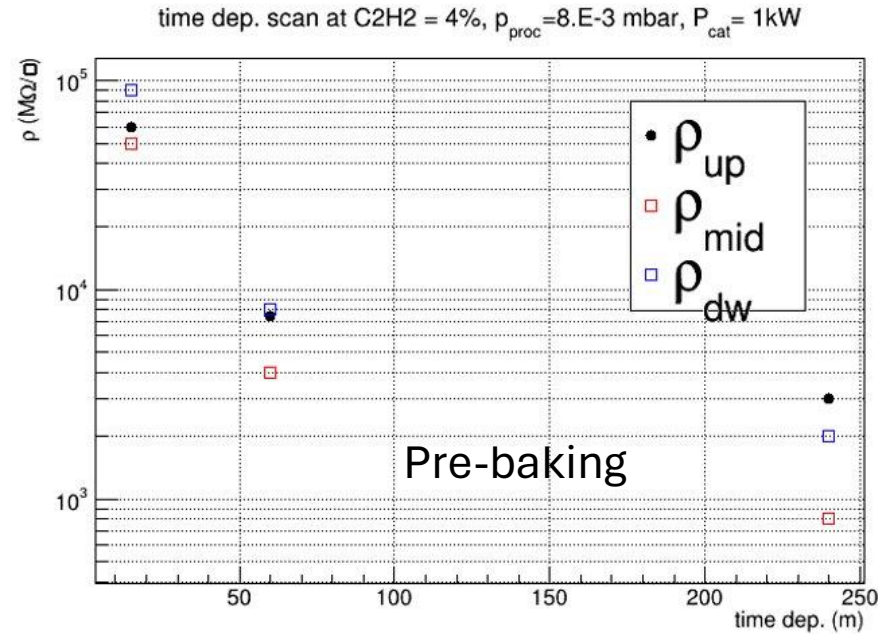
Stability with C₂H₂ (Sept. - Oct. 2023)

C₂H₂ 2%, p_{proc} = 2E-3 mbar, t_{dep} = 15 min, P_{cat} = 1kW

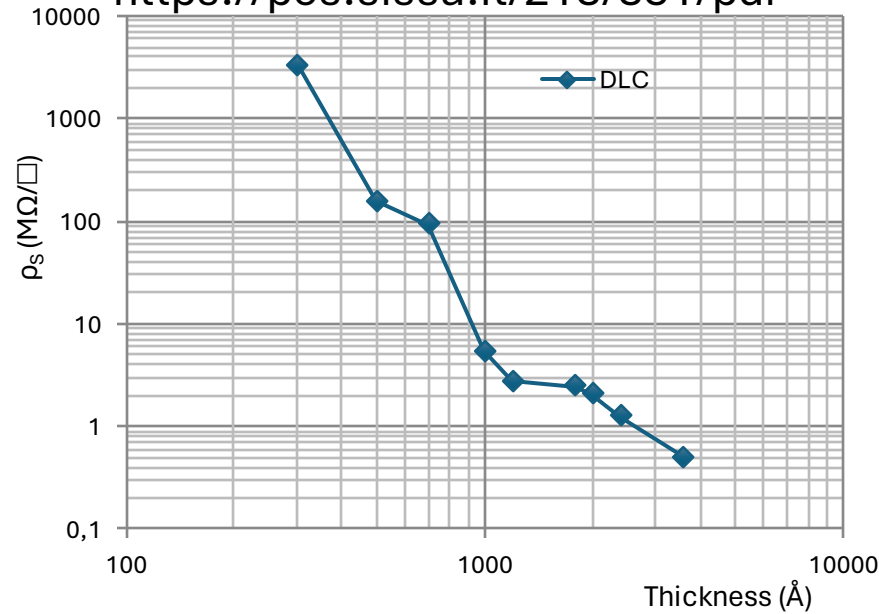


A drop after the baking and a small drift, but then very stable values

Deposition time and repetitivity test

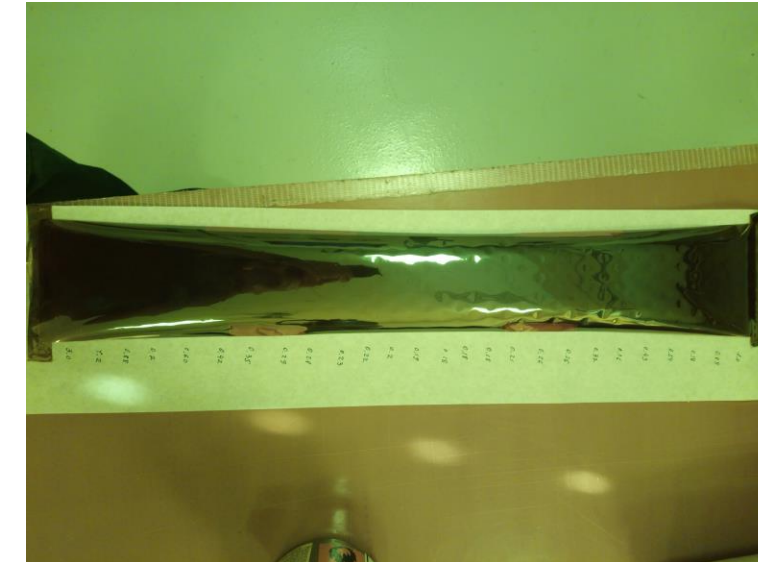
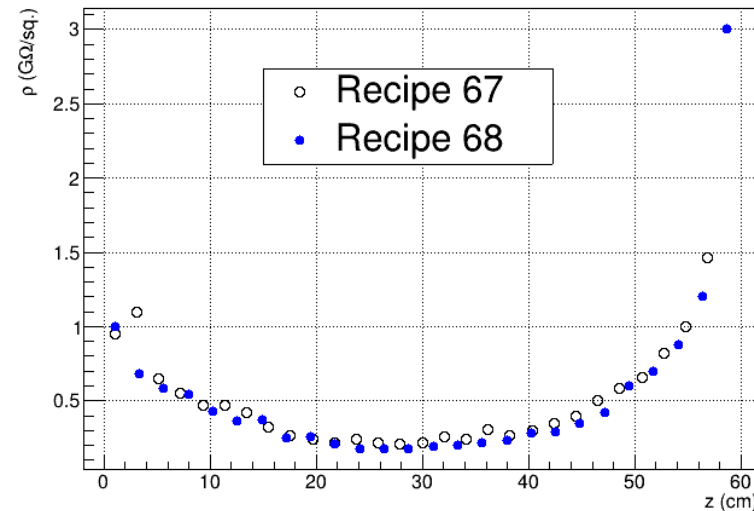


<https://pos.sissa.it/213/351/pdf>



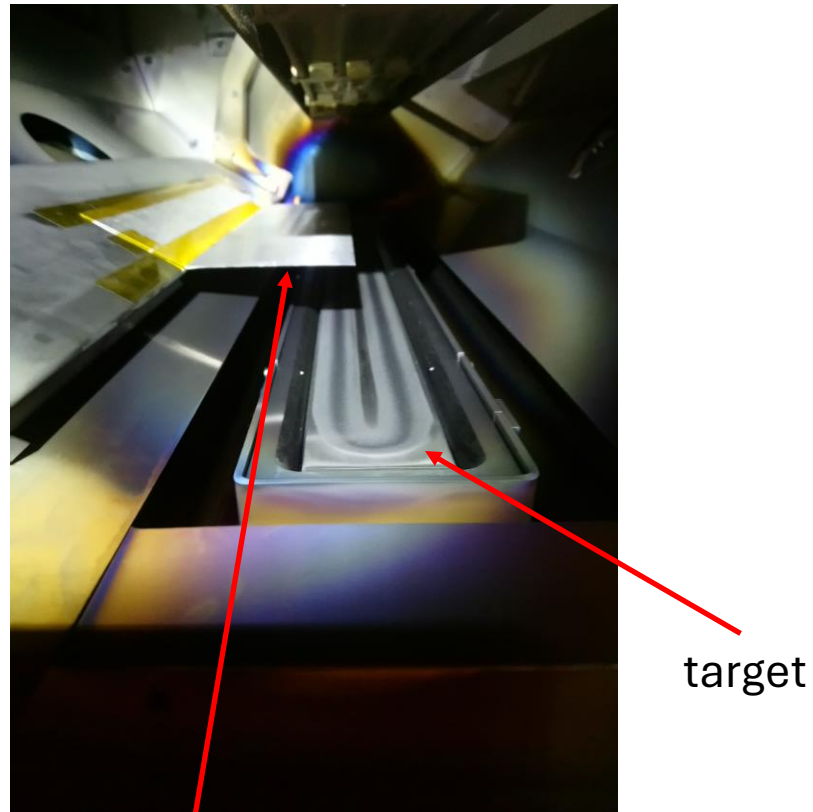
Confirmed the behaviour $f(1/t)$
 Time can be an important parameter for the resistivity adjustment
WARNING = evidence of non-uniformity along z!

C2H2 3%, 2.E-3 mbar, time = 22.5 min, P = 1 kW



From now on, we use a single APICAL sample 60 x 10 cm²
 We measure the resistivity along the longitudinal axis

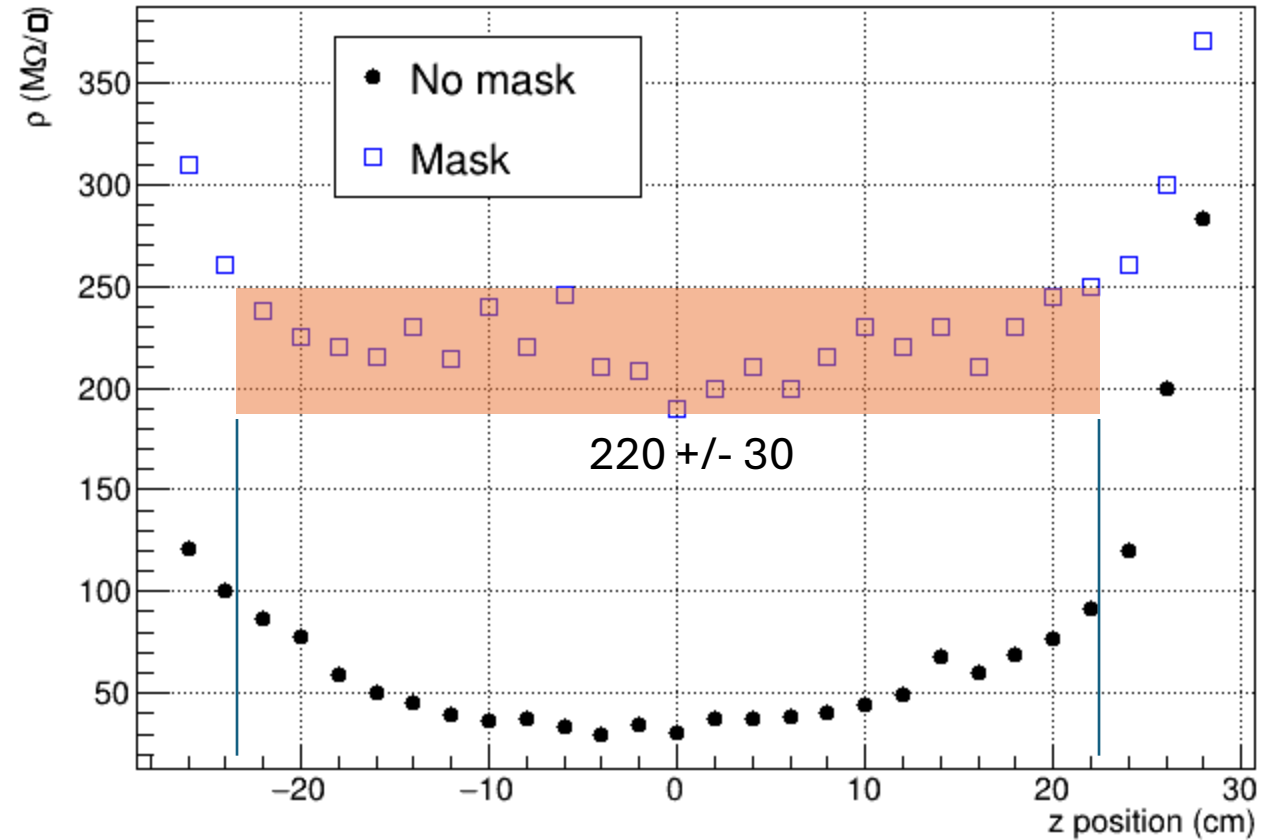
Summary of the test with C₂H₂ (Nov. 2023)



mask

target

Ar 150 sccm, C₂H₂ 3 sccm, p_{proc} 2E-3 mbar



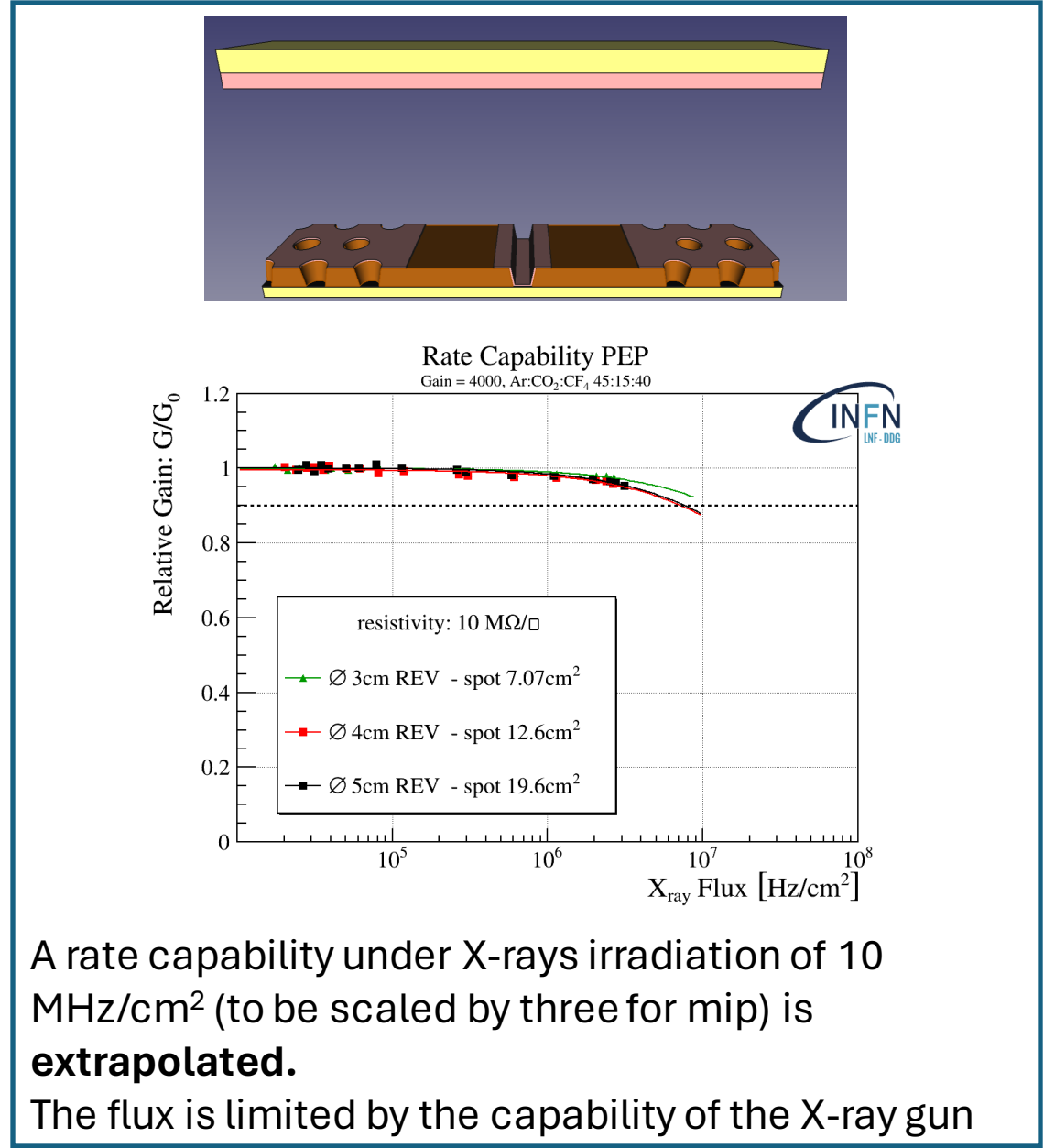
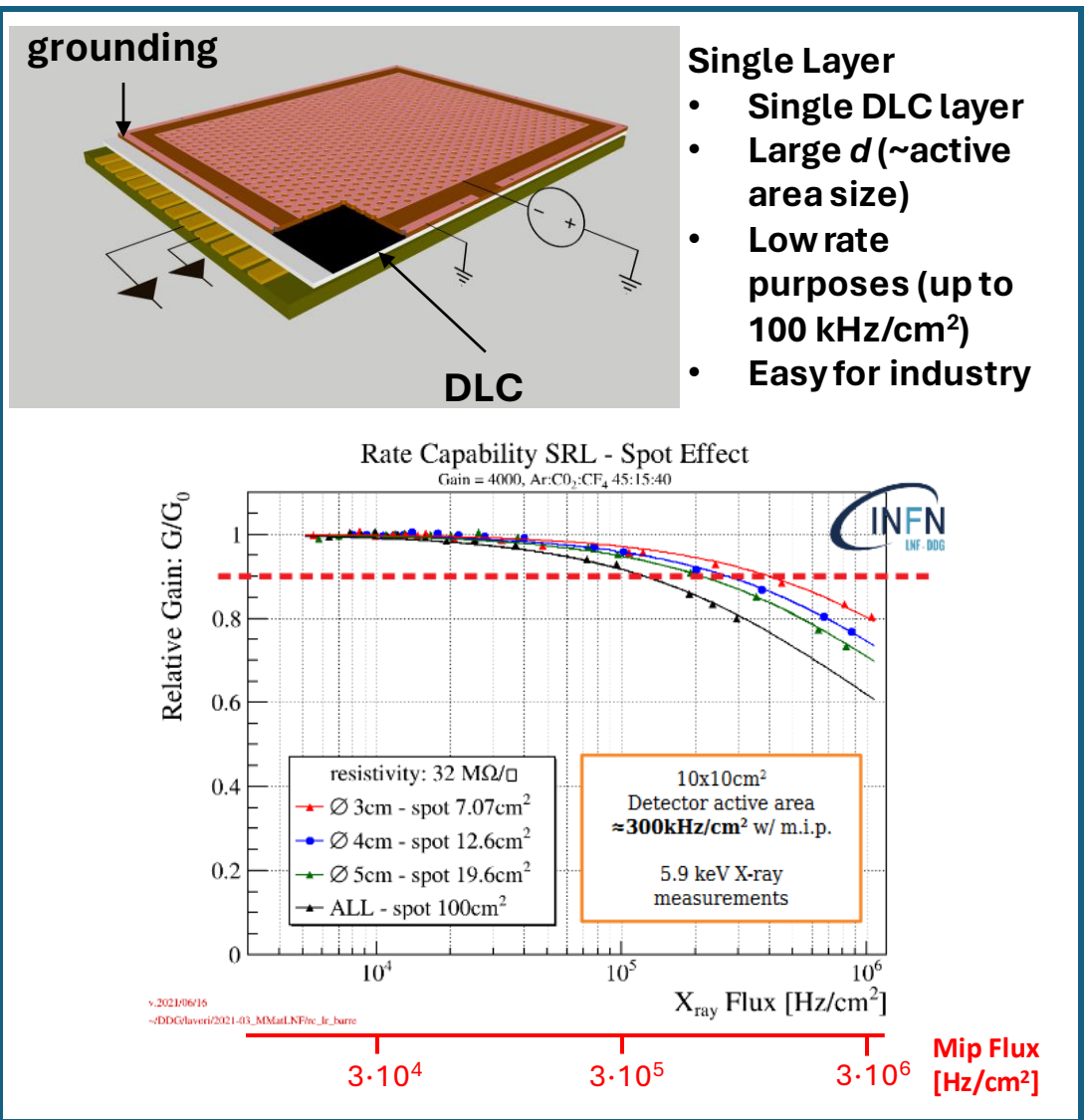
The mask seems promising. The uniformity region has been extended to about 45 cm. Further improvements can be achieved with a different mask shape

Conclusions

- The community shows a huge interest in resistive materials, since they can improve the stability of the detectors
- In RPCs field new lower bulk resistive materials have been introduced to improve the rate capability keeping the other features unchanged
- A link from bulk resistive material borrowed by MPGDs with the birth of RPWELL
- The DLC created another strong link between the MPGD technologies and the RPC world with the introduction of the sRPC technology

- The presence of the CID machine at CERN should provide a remarkable production of this resistive material for the early mentioned applications
- The tests done so far are very promising
- The production is likely to start in 2024

Micro-Pattern Gaseous Detectors



DLC tests

The machine phase-space is quite huge; the plan for the tests have been focused to few parameters.

QUICK GLOSSARY

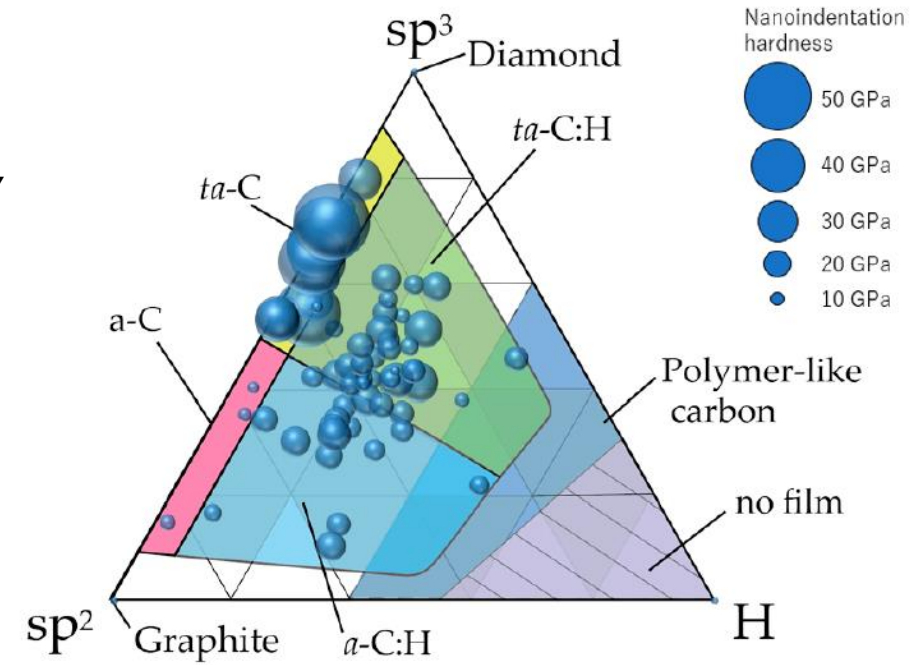
Pressure limit: *the pressure of the vacuum at which the run starts. Typically 2.E-5 mbar*

Pressure process: *the pressure of the plasma during the sputtering phase*

Power: *the maximum power limit output from the DC PS on the cathode*

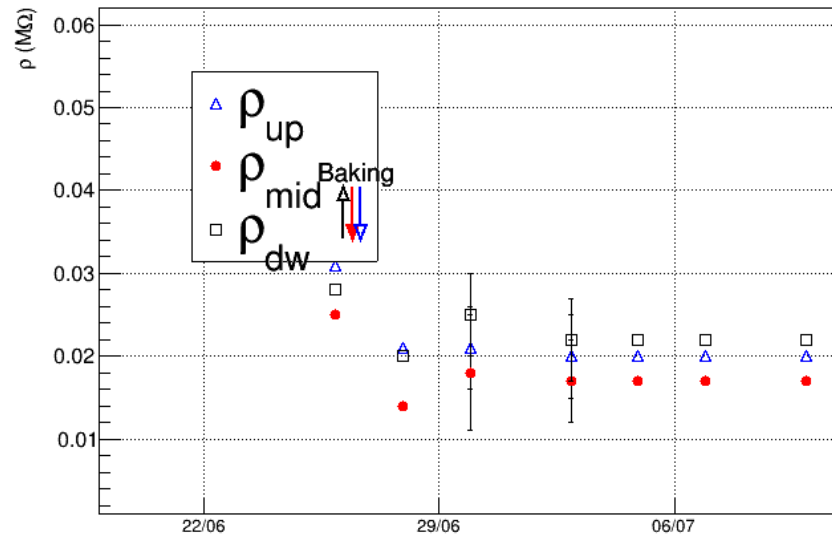
Time deposition: *the duration of the sputtering process*

- Ar-N₂ plasma tests
 - Scan in nitrogen percentage at a given pressure process
 - Scan in pressure process at a given nitrogen percentage
 - Tests with different time deposition
- Ar-C₂H₂ plasma tests
 - Scan in acetylene percentage at a given pressure process and power
 - Scan in time deposition at a given pressure process, acetylene percentage and power
 - Uniformity tests

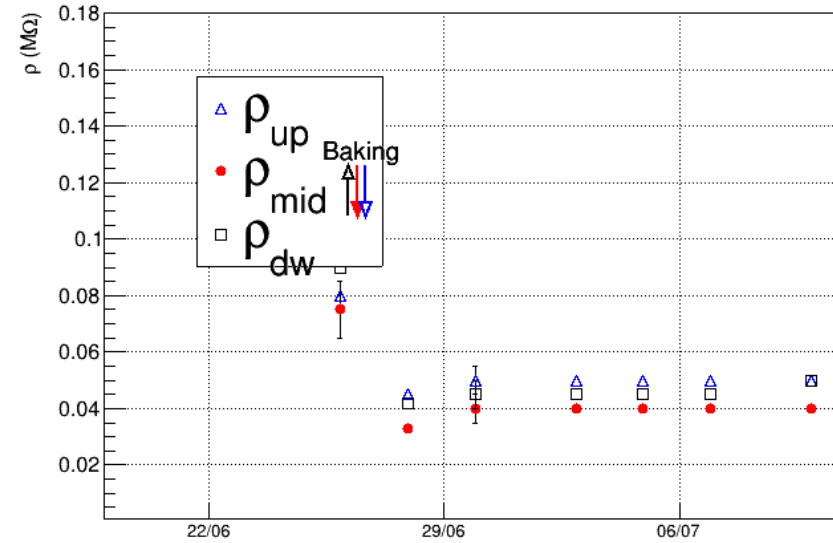


Tests in pure Argon

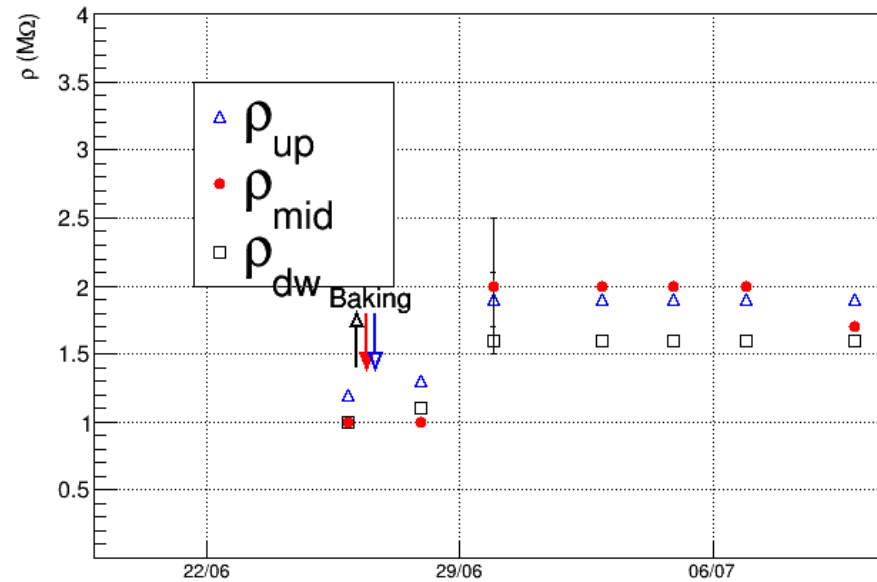
test14, pproc=1.E-2 mbar, N2=0%, tproc=15min



test15, pproc=6.E-3 mbar, N2=0%, tproc=15min



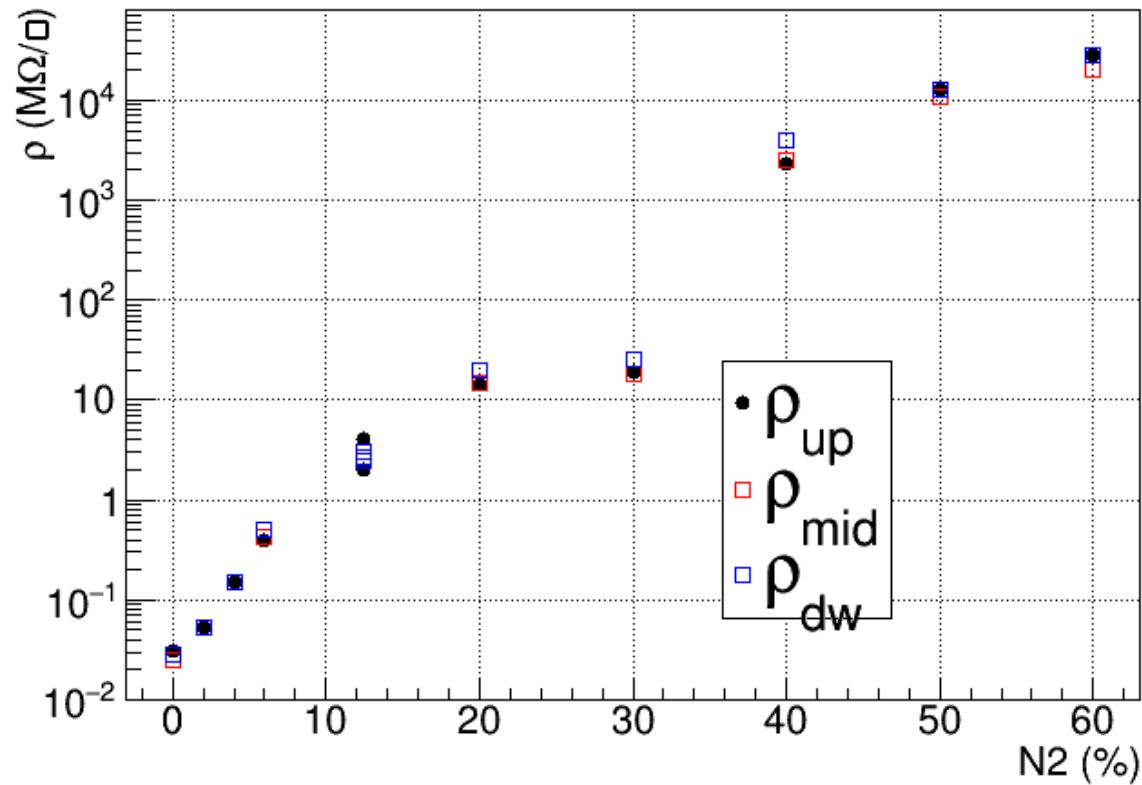
test16, pproc=2.E-2 mbar, N2=0%, tproc=15min



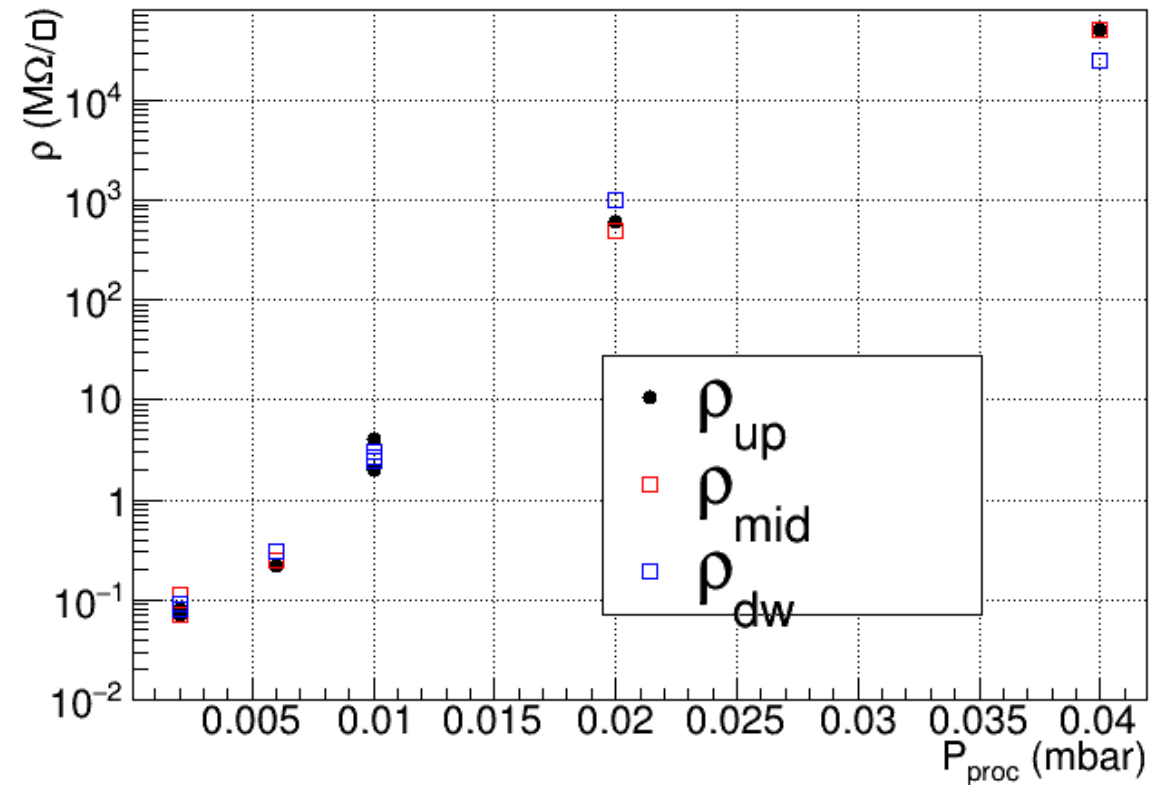
Summary of the test with N₂ (June 2023)

Nevertheless these tests have been helpful to understand the dependance of the resistivity on the quantity of the second component of the plasma and on the pressure process

N₂ scan at $p_{\text{proc}} = 1.E-2$ mbar and $\Delta t_{\text{proc}} = 15$ min



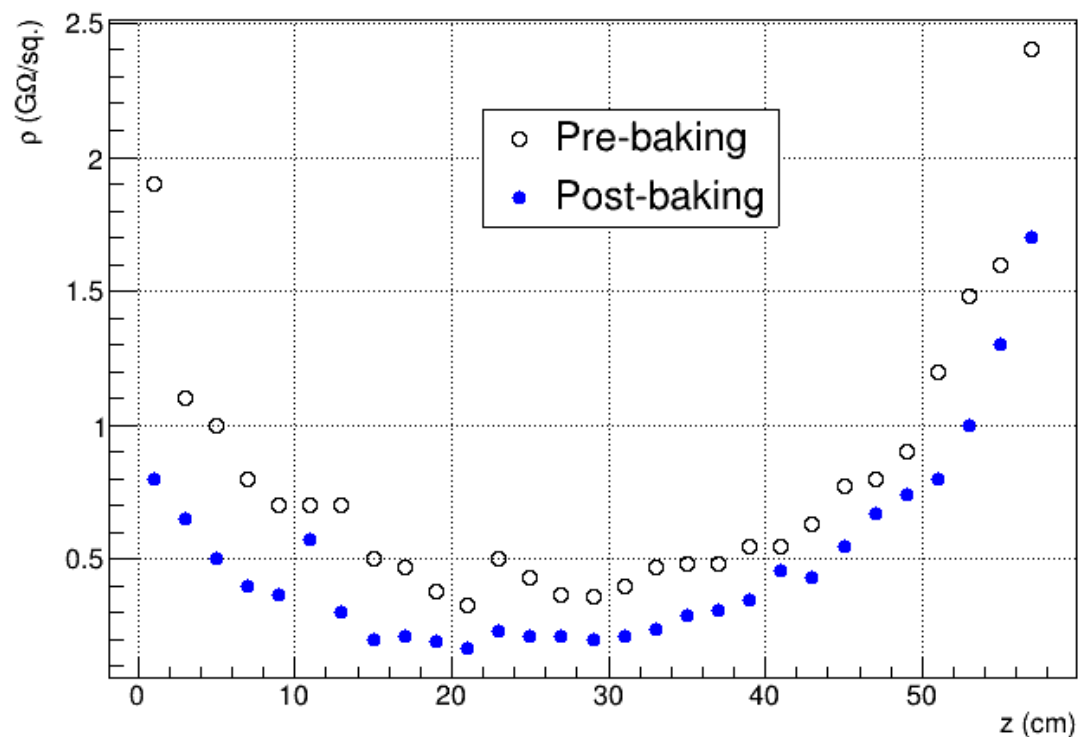
P_{proc} scan at 12.5% N₂ and $\Delta t_{\text{proc}} = 15$ min



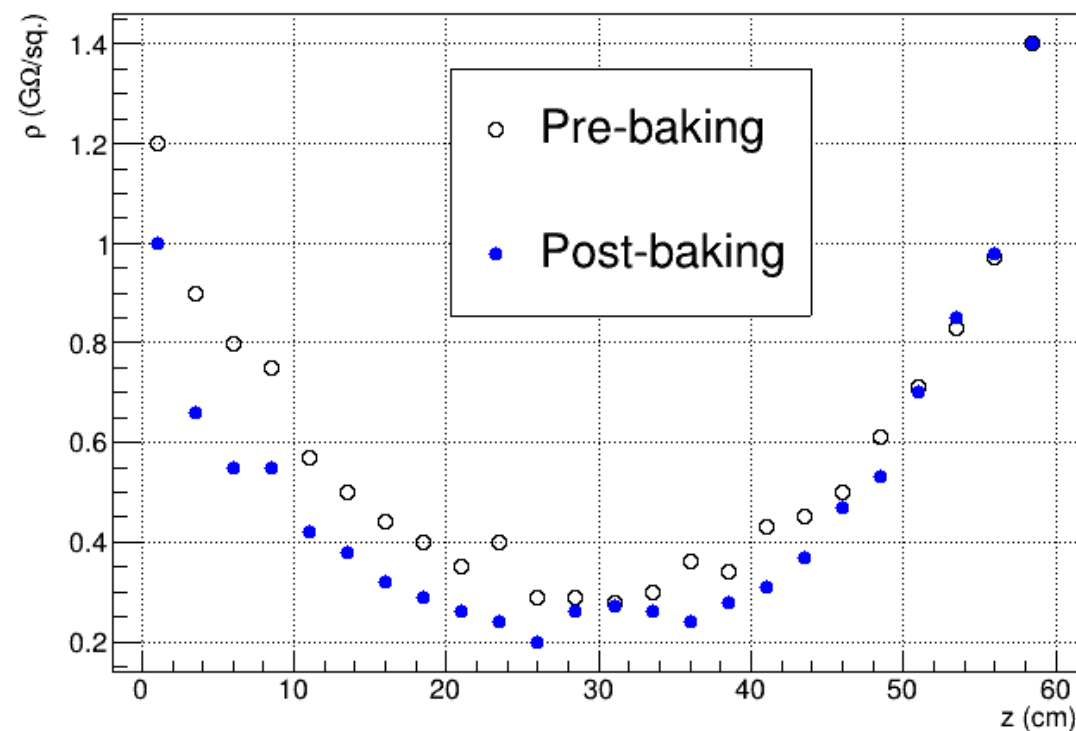
Very large amount of nitrogen to reach the target resistivity (50–200 Mohm/sq.)

Uniformity test

C2H2 4%, 2.E-3 mbar, time = 15 min, P = 1 kW



C2H2 5%, 2.E-3 mbar, time = 10 min, P = 2 kW



The baking, as expected, doesn't change the thickness profile

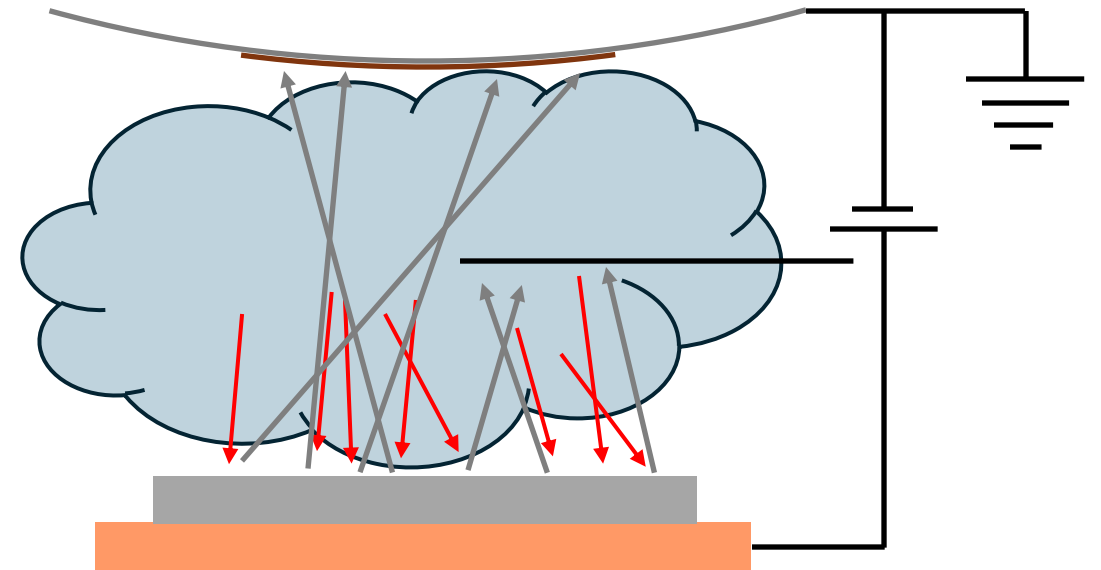
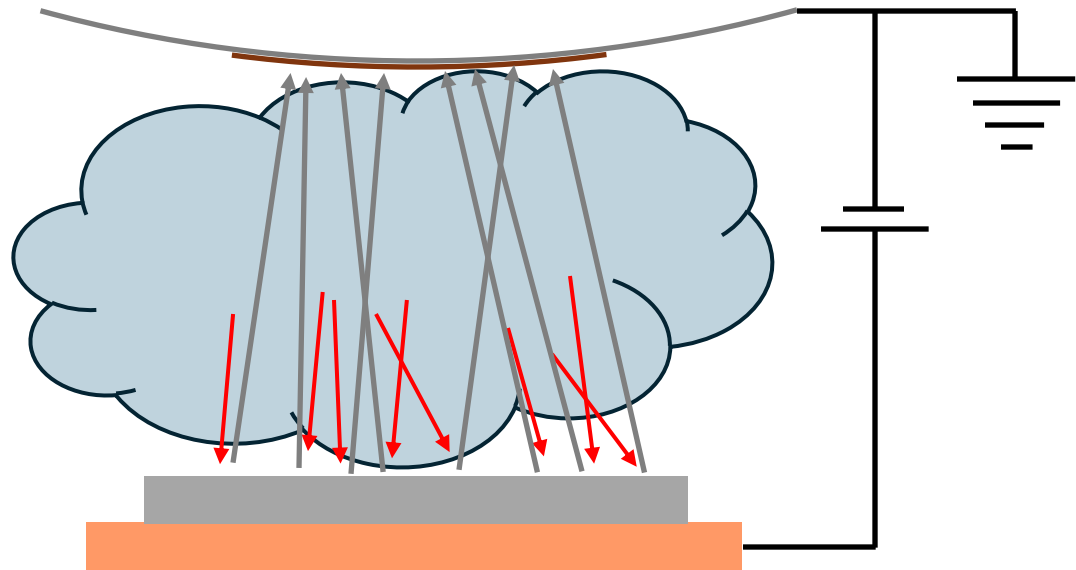
These tests pointed out that the deposition, along the axis, is uniform in a very narrow central region

We would like to have a uniformity $\leq 15\%$

THIS REGION MUST BE EXTENDED

Summary of the test with C₂H₂ (Nov. 2023)

To improve the uniformity, Serge's idea is to install a mask stuck to the shutter to reduce the material extraction in the central part of the target



Lower extraction → thinner deposition → larger resistivity

